

<b>Notice of References Cited</b>	Application/Control No. 10/565,876	Applicant(s)/Patent Under Reexamination SHIN, HEE-SEOK	
	Examiner Thanh-Tam T. Le	Art Unit 2839	Page 1 of 1

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*	B	US-6,203,345 B1	03-2001	Roque et al.	439/260
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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